



Jonathan Angle <jangle9@vt.edu>

Thu, Mar 10,  
12:37 PM (8  
days ago)

to Fred

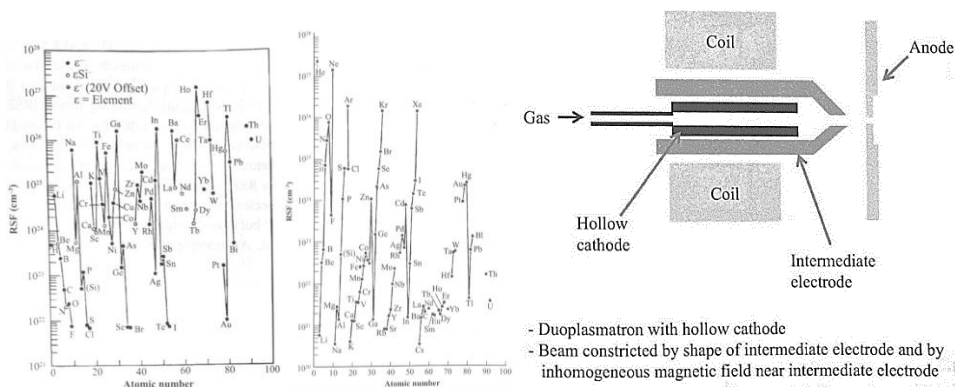
Hi Fred,

As you know I am approaching the end of my PhD journey and I wanted to thank you for the years of help and guidance. I truly can't express my gratitude enough.

In my dissertation I have used a few images from your SIMS book (Stevie 2016). I am asking for permission to republish these images for my dissertation. For Convenience, I pasted the images I wish to use to this email. If you approve of this, you can simply reply back to this email. I look forward to presenting to you Monday.

Thanks,

Jonny



Fred Stevie

Thu, Mar 10,  
12:46 PM (8  
days ago)

to me

Jonny,

You have permission to use the images. See you Monday.

Fred

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Fred Stevie  
Analytical Instrumentation Facility  
North Carolina State University  
2410 Campus Shore Drive

MRC Building Room 318  
Raleigh, NC 27695-7531  
(919) 515-7037      [fred\\_stevie@ncsu.edu](mailto:fred_stevie@ncsu.edu)

**Jonathan Angle <jangle9@vt.edu>**

Wed, Mar 9,  
11:45 AM (9  
days ago)

to Marc, Charlie

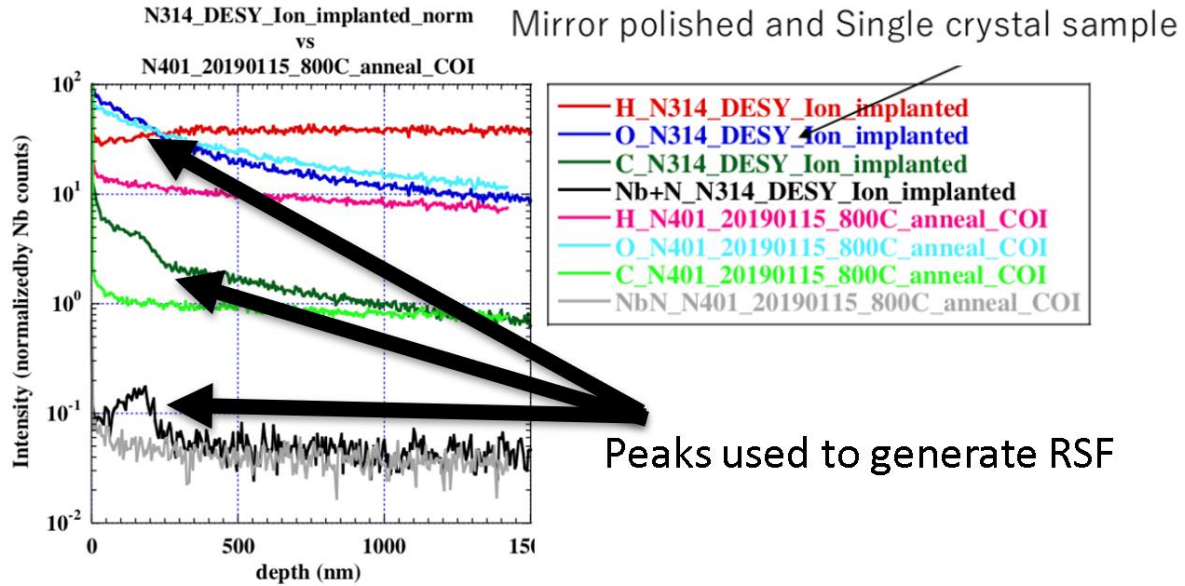
Hi Marc,

I hope you have been doing well since the last time we spoke. I am slated to finish my Ph.D. very soon and I would like to use an image that you shared with me previously which reflects challenges using ToF SIMS for quantitative measures. I am requesting permission to use this image in my dissertation, in which you will be given credit for its usage. For convenience, I have pasted the image to this email for you to refer back to it.

I thank you very much for your consideration on this matter. If you grant the permission, you can simply reply back to this email saying that you approve. I wish you all the best and hope to have more engaging conversations at future SRF conferences.

Warm Regards,

Jonathan Angle  
Ph.D. Candidate/SIMS Manager  
Materials Science and Engineering  
Virginia Polytechnic Institute and State University



**Marc Wenskat**

Wed, Mar 9,  
11:50 AM (9  
days ago)

to Taro, me, Charlie

Dear Jonathan, Dear Charlie,

I included Taro Konomi in cc, as I was using this plot, but the measurement and the plot was done by him. Hence I would ask him if he approves the usage of the plot by you.

All the best,

Marc

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Dr. Marc Wenskat  
Phone: (+49) 040-8998-2032  
email: [marc.wenskat@desy.de](mailto:marc.wenskat@desy.de)  
Universität Hamburg - Campus Bahrenfeld | Notkestrasse 85 D-22607 Hamburg |  
Bldg. 30b Room 467

**Jonathan Angle <jangle9@vt.edu>**

Wed, Mar 9,  
12:24 PM (9  
days ago)

to Marc, Charlie, Taro

Hello everyone,

Thank you Marc for the speedy response!

Taro, I apologize for excluding you in the original email, as Marc correctly pointed out that you are the originator of this data. I mentioned before that I would like to include this plot into my dissertation and I would give you credit for the plot. If you do approve, you can simply reply to this email saying that you approve. The plot I wish to use is pasted into this email chain.

I also hope that we can catch up at a future SRF meeting!

Thanks,

Jonathan Angle  
Ph.D. Candidate/SIMS Manager  
Materials Science and Engineering  
Virginia Polytechnic Institute and State University

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**konomi@post.kek.jp**

Wed, Mar 9,  
5:58 PM (9  
days ago)

to me, Marc, Charlie

Dear Jonathan and Marc,

There is no problem with using the data.

After all, the surface analysis did not go well for N-infusion with my own power at KEK.

I am very interested to your paper.

With my best regards,

Taro

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**Jonathan Angle <jangle9@vt.edu>**

Thu, Mar 10,  
12:11 PM (8  
days ago)

to taro.konomi, Marc, Charlie

Taro,

Thank you very much. I will be happy to share it when the defense is completed, which should be pretty soon. The process should be completed within two weeks or so. Also if we wish to revisit method improvement for SIMS quantitation, I would be happy to do so.

Warm regards,

Jonathan Angle  
Ph.D. Candidate/SIMS Manager  
Materials Science and Engineering  
Virginia Polytechnic Institute and State University